ESD TEST REPORT

Field-Induced Charged-Device Model
JS-002-2014

ANSI/ESDA/JEDEC Standard, Method JS-002-2014 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

Customer : **Chongqing Alpha and Omega Semiconductor Limited**

Address: No. 288 Yuefu Road, Beibei District, Chongqing, P.R. China

Device Information

Part No. :	AONR21311C	Sample Size :	3pcs
Package Type :	DFN3x3-8L-EP	Pin Count :	8
Lot No. :	AZS0925.01(NL0S11)	Date Code :	-
VDD Domains :	D	VSS Domains :	S

Test Equipment

Tester1 :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jan 15th 2020	Expiration Date :	Jan 14th 2021
Tester2 :	Orion Robotic CDM Test System	Serial No. :	0806294
Calibration Date :	Oct 11th 2019	Expiration Date :	Oct 10th 2020

Environmental Condition

Temperature :	23ºC	Humidity :	30% RH
Submit date :	Jul 24th 2020	Complete date :	Jul 24th 2020

Curve Trace Criteria

Pin Combinations			Force Voltage	Limit current
D	Vs.	S & G	-30V ~ +30V	50μA

Curve Trace Results Within 10% range.

Stress Summary

CDM			
Sample No.	Voltage Level	Process	Spot Test Results* (Within -10μA @ -20V between G and D/S)
12#	±2kV	All Pins Done	PASS
13#		All Pins Done	PASS
14#		All Pins Done	PASS

Test Result*

Model	Pin Combinations	ESD Sensitivity Pass*: **2kV**	V Class: **C3**
CDM	ALL PINS DONE	±2kV	JS-002-2014 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: ≥1000V

***Note: Results will be updated based on customer final electrical test results.**

Test Engineer: Fei Teng	Date: Jul 24th 2020
Approved by FA Manager: 李春	Date: Jul 24th 2020

Evans Materials Technology (Shanghai) Co., Ltd. 埃文思材料科技(上海)有限公司 报告专用章

Recommendations

EAG Shanghai certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

EAG Shanghai recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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